



<b>Search Notes</b>  	Application/Control No.  09467851	Applicant(s)/Patent Under Reexamination  LEAK ET AL.
	Examiner Tran, Hai	Art Unit 2623


Notes	Date	Examiner
Son Huynh (725)	09/26/2006	HVT
Rueben Brown (725)	09/26/2006	HVT
U.S. Patent and Trademark Office		Part of Paper No.: 20060929

<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>09467851</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>LEAK ET AL.</p>
	<p>Examiner</p> <p>Tran, Hai</p>	<p>Art Unit</p> <p>2623</p>

Class	SubClass	Date	Examiner
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725	59-61,109,112,131,136,139	09/29/2006	HVT
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<b><i>Interference Searched</i></b>  	Application/Control No.  09467851	Applicant(s)/Patent Under Reexamination  LEAK ET AL.
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see Attached Interference  
Searched

09/29/2006

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